

DOT: new deterministic defect-oriented ATPG tool

Raik, Jaan; Ubar, Raimund-Johannes; Sudbrock, Joachim; Kuzmich, Wieslaw; Pleskacz, Witold A. European Test Symposium : ETS 2005 : 22-25 May 2005, Tallinn, Estonia : proceedings 2005 / p. 96-101 : ill

Energy minimization for hybrid BIST in a system-on-chip test environment

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